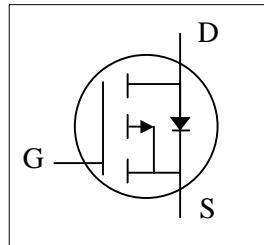
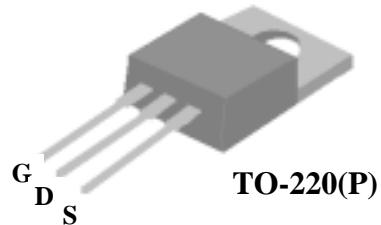
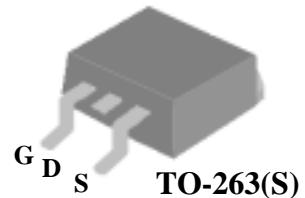




- ▼ Lower On-resistance
- ▼ Simple Drive Requirement
- ▼ Fast Switching Characteristic
- ▼ RoHS Compliant



$BV_{DSS}$	-100V
$R_{DS(ON)}$	210mΩ
$I_D$	-16A



## Description

The Advanced Power MOSFETs from APEC provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-263 package is universally preferred for all commercial-industrial surface mount applications and suited for low voltage applications such as DC/DC converters. The through-hole version (AP15P10GP) are available for low-profile applications.

## Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	-100	V
$V_{GS}$	Gate-Source Voltage	$\pm 20$	V
$I_D @ T_C=25^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10\text{V}$	-16	A
$I_D @ T_C=100^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10\text{V}$	-9.8	A
$I_{DM}$	Pulsed Drain Current <sup>1</sup>	64	A
$P_D @ T_C=25^\circ\text{C}$	Total Power Dissipation	96	W
	Linear Derating Factor	0.77	W/°C
$T_{STG}$	Storage Temperature Range	-55 to 150	°C
$T_J$	Operating Junction Temperature Range	-55 to 150	°C

## Thermal Data

Symbol	Parameter	Value	Units
$R_{thj-c}$	Thermal Resistance Junction-case	Max. 1.3	°C/W
$R_{thj-a}$	Thermal Resistance Junction-ambient	Max. 62	°C/W



## Electrical Characteristics@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

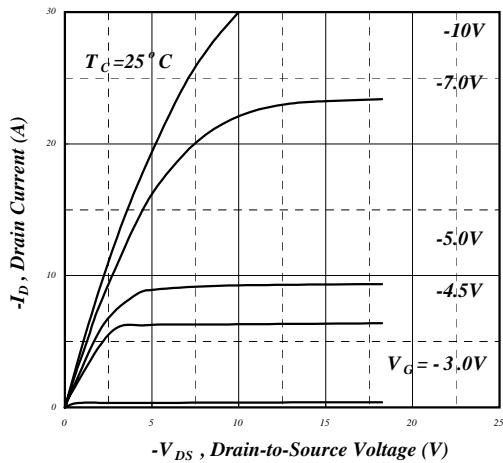
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$ , $I_{\text{D}}=-1\text{mA}$	-100	-	-	V
$\Delta \text{BV}_{\text{DSS}}/\Delta T_j$	Breakdown Voltage Temperature Coefficient	Reference to $25^\circ\text{C}$ , $I_{\text{D}}=-1\text{mA}$	-	-0.1	-	$\text{V}/^\circ\text{C}$
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance <sup>2</sup>	$V_{\text{GS}}=-10\text{V}$ , $I_{\text{D}}=-9\text{A}$	-	-	210	$\text{m}\Omega$
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}$ , $I_{\text{D}}=-250\mu\text{A}$	-1	-	-3	V
$g_{\text{fs}}$	Forward Transconductance	$V_{\text{DS}}=-10\text{V}$ , $I_{\text{D}}=-9\text{A}$	-	8	-	S
$I_{\text{DSS}}$	Drain-Source Leakage Current ( $T_j=25^\circ\text{C}$ )	$V_{\text{DS}}=-100\text{V}$ , $V_{\text{GS}}=0\text{V}$	-	-	-25	$\mu\text{A}$
	Drain-Source Leakage Current ( $T_j=150^\circ\text{C}$ )	$V_{\text{DS}}=-80\text{V}$ , $V_{\text{GS}}=0\text{V}$	-	-	-100	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Source Leakage	$V_{\text{GS}}=\pm 20\text{V}$	-	-	$\pm 100$	nA
$Q_g$	Total Gate Charge <sup>2</sup>	$I_{\text{D}}=-9\text{A}$	-	37	60	nC
$Q_{\text{gs}}$	Gate-Source Charge	$V_{\text{DS}}=-80\text{V}$	-	5	-	nC
$Q_{\text{gd}}$	Gate-Drain ("Miller") Charge	$V_{\text{GS}}=-10\text{V}$	-	15	-	nC
$t_{\text{d(on)}}$	Turn-on Delay Time <sup>2</sup>	$V_{\text{DS}}=-50\text{V}$	-	11	-	ns
$t_r$	Rise Time	$I_{\text{D}}=-9\text{A}$	-	25	-	ns
$t_{\text{d(off)}}$	Turn-off Delay Time	$R_G=10\Omega$ , $V_{\text{GS}}=-10\text{V}$	-	56	-	ns
$t_f$	Fall Time	$R_D=5.6\Omega$	-	36	-	ns
$C_{\text{iss}}$	Input Capacitance	$V_{\text{GS}}=0\text{V}$	-	1180	1900	pF
$C_{\text{oss}}$	Output Capacitance	$V_{\text{DS}}=-25\text{V}$	-	250	-	pF
$C_{\text{rss}}$	Reverse Transfer Capacitance	f=1.0MHz	-	75	-	pF
$R_g$	Gate Resistance	f=1.0MHz	-	3.6	5	$\Omega$

## Source-Drain Diode

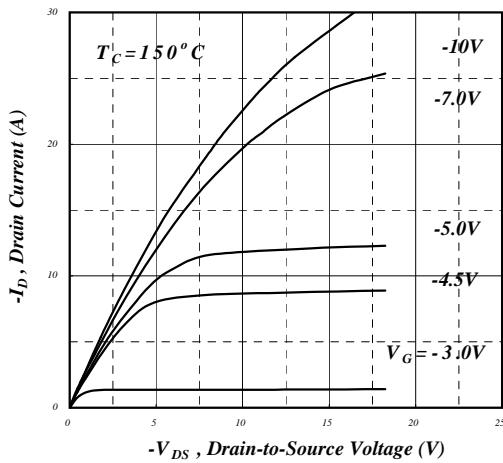
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$V_{\text{SD}}$	Forward On Voltage <sup>2</sup>	$I_S=-9\text{A}$ , $V_{\text{GS}}=0\text{V}$	-	-	-1.3	V
$t_{\text{rr}}$	Reverse Recovery Time <sup>2</sup>	$I_S=-9\text{A}$ , $V_{\text{GS}}=0\text{V}$ ,	-	95	-	ns
$Q_{\text{rr}}$	Reverse Recovery Charge	$dI/dt=-100\text{A}/\mu\text{s}$	-	410	-	nC

## Notes:

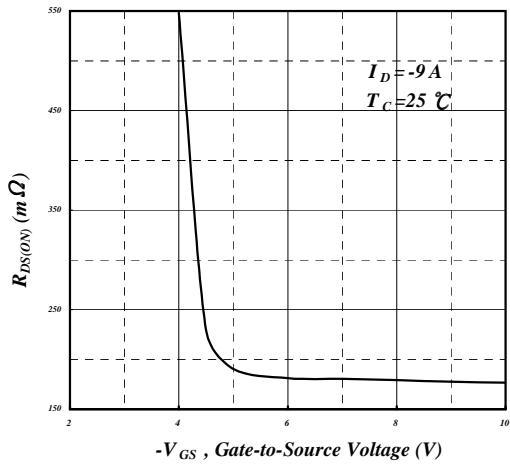
- 1.Pulse width limited by safe operating area.
- 2.Pulse width  $\leq 300\mu\text{s}$  , duty cycle  $\leq 2\%$ .



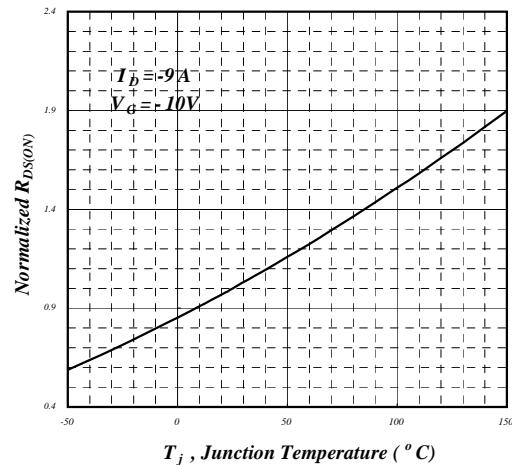
**Fig 1. Typical Output Characteristics**



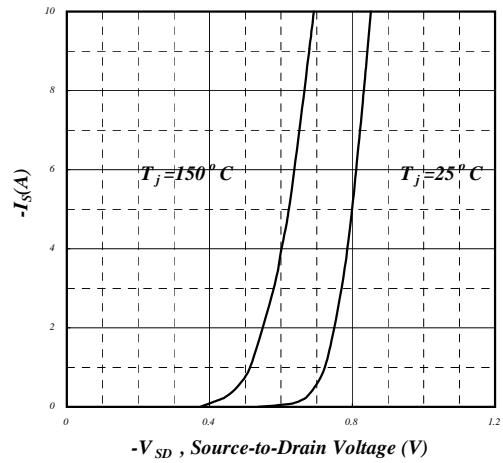
**Fig 2. Typical Output Characteristics**



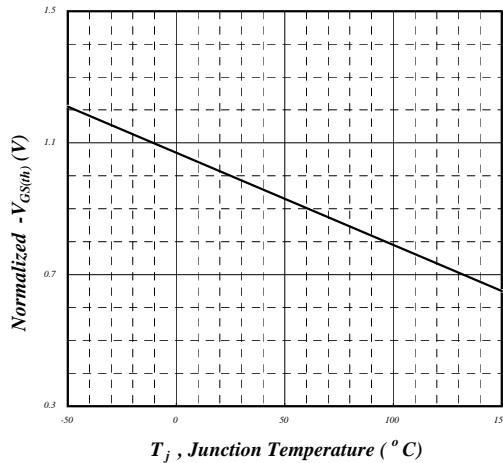
**Fig 3. On-Resistance v.s. Gate Voltage**



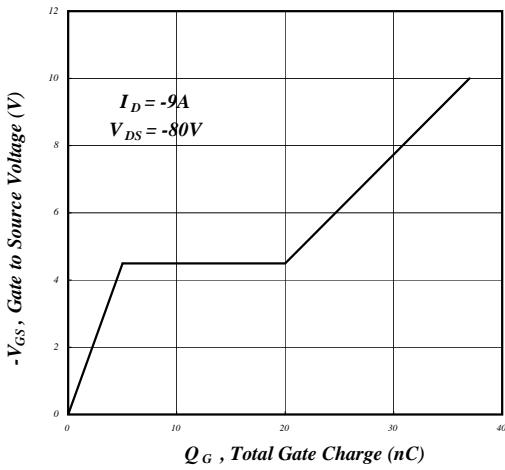
**Fig 4. Normalized On-Resistance v.s. Junction Temperature**



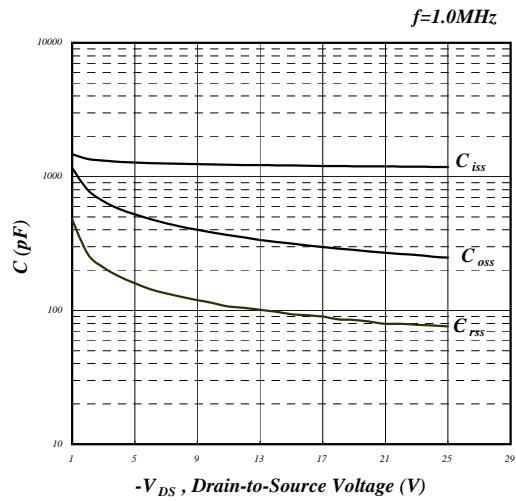
**Fig 5. Forward Characteristic of Reverse Diode**



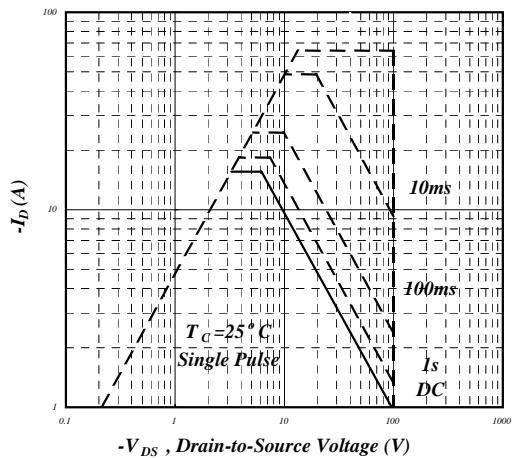
**Fig 6. Gate Threshold Voltage v.s. Junction Temperature**



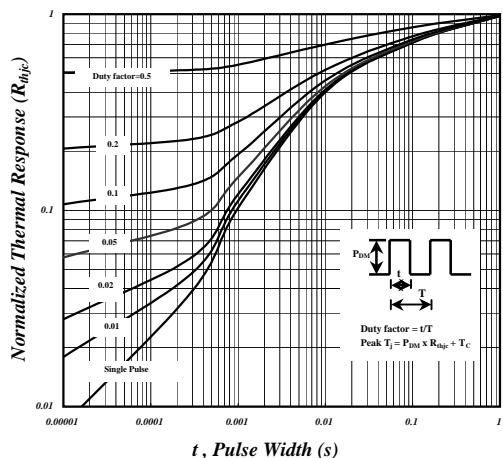
**Fig 7. Gate Charge Characteristics**



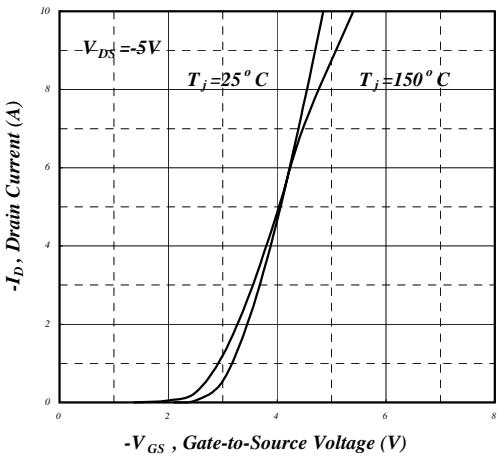
**Fig 8. Typical Capacitance Characteristics**



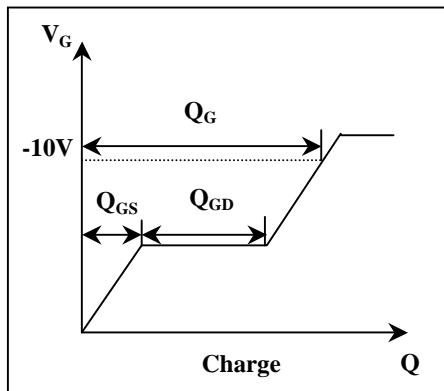
**Fig 9. Maximum Safe Operating Area**



**Fig 10. Effective Transient Thermal Impedance**



**Fig 11. Transfer Characteristics**



**Fig 12. Gate Charge Waveform**